

<b>Notice of References Cited</b>	Application/Control No. 10/561,895	Applicant(s)/Patent Under Reexamination RITTER ET AL.	
	Examiner JOSE R. DIAZ	Art Unit 2815	Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,112,865	09-2006	Fujihira et al.	257/484
*	B	US-6,633,071	10-2003	Furio, Cyril	257/383
*	C	US-5,416,354	05-1995	Blackstone, Scott C.	257/499
*	D	US-4,965,643	10-1990	Freeman, Guy R.	257/73
*	E	US-4,454,523	06-1984	Hill, Lorimer K.	257/264
*	F	US-4,228,448	10-1980	Lalumia et al.	257/474
*	G	US-4,156,246	05-1979	Pedersen, Richard A.	257/474
*	H	US-4,107,719	08-1978	Graul et al.	257/474
*	I	US-4,104,732	08-1978	Hewlett, Jr., Frank Wilson	365/179
*	J	US-4,089,020	05-1978	Ikedo et al.	257/475
*	K	US-4,062,033	12-1977	Suzuki, Kunizo	257/474
*	L	US-3,909,837	09-1975	Kronlage, John William	257/479
*	M	US-3,846,192	11-1974	Murmann	438/328

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2184599 A	06-1987	United Kingdom	BERTOTTI et al.	
	O	JP 56090565 A	07-1981	Japan	SHIMADA et al.	
	P	JP 61048970 A	03-1986	Japan	UCHIDA et al.	
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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